

LIST OF ART CITED BY APPLICANT



PTO-1449)

ATTY. DOCKET NO.
HSI-0001APPLN. SERIAL NO.
10/621,471

APPLICANT(S)

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FILING DATE

July 18, 2003

GROUP

2812

U.S. PATENT DOCUMENTS

EXAMINER'S INITIALS	*PATENT NO.	*ISSUE DATE	*INVENTOR NAME	CLASS	SUBCLASS	FILING DATE
RRB	6,179,923 B1	01/30/2001	Yamamoto et al.	118	719	08/18/1998
RRB	6,237,529 B1	05/29/2001	Spahn	118	726	03/03/2000

U.S. PATENT APPLICATION PUBLICATIONS

*PATENT APPLN. PUB. NO.	*PUB. DATE	*APPLICANT	CLASS	SUBCLASS

U.S. PATENT APPLICATIONS

*APPLN. NO.	*FILING DATE	*INVENTOR	CLASS	SUBCLASS

FOREIGN PATENT DOCUMENTS

EXAMINER'S INITIALS	PATENT NO.	DATE	COUNTRY	CLASS	SUBCLASS	Translation	
						Yes	No
RRB	EP 0 028 514 A1	05/13/1981	Europe			X	
RRB	EP 0 826 434 A1	03/04/1998	Europe			X	
RRB	EP 0 887 434 A1	12/30/1998	Europe			X	
RRB	EP 0 967 667 A2	12/29/1999	Europe			X	
RRB	EP 1 078 999 A2	02/28/2001	Europe			X	
RRB	EP 1 113 087 A2	07/04/2001	Europe			X	
RRB	EP 1 167 566 A1	01/02/2002	Europe			X	
RRB	JP 60026660	02/09/1985	Japan (English Abstract & Japanese Full Text)			X	
RRB	JP 60086270	05/15/1985	Japan (English Abstract & Japanese Full Text)			X	
RRB	JP63014861	01/22/1988	Japan (English Abstract & Japanese Full Text)			X	
RRB	JP 2000248358	09/12/2000	Japan (English Abstract & Japanese Full Text)			X	

OTHER ART (Including Author, Title, Date, Pertinent Pages, Publisher, Place of Publication, Etc.)

Search Report issued on April 6, 2004 by the European Patent Office.

EXAMINER	DATE CONSIDERED
R Buh	7-2005

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